

The LIGO logo consists of several concentric, curved lines on the left side, resembling a stylized 'L' or a series of ripples. To the right of these lines, the word "LIGO" is written in a bold, black, sans-serif font.

LIGO

Frequency Stabilization of 2 Micron Lasers Using Optical Delay Self-Heterodyne Interferometry

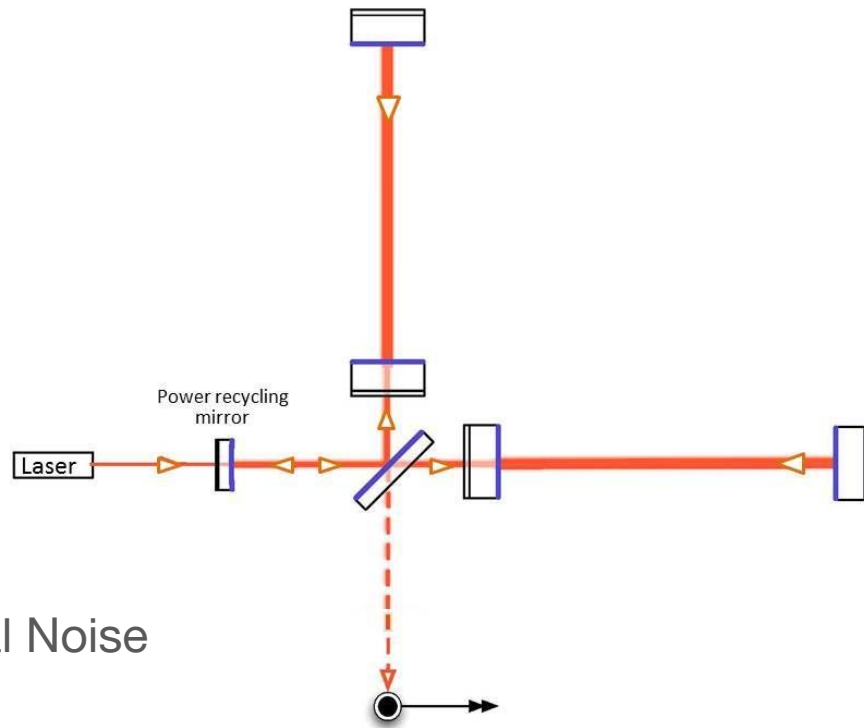
Stella Kraus, Hannah Rose

Mentors: Aidan Brooks, Rana Adhikari

Caltech¹

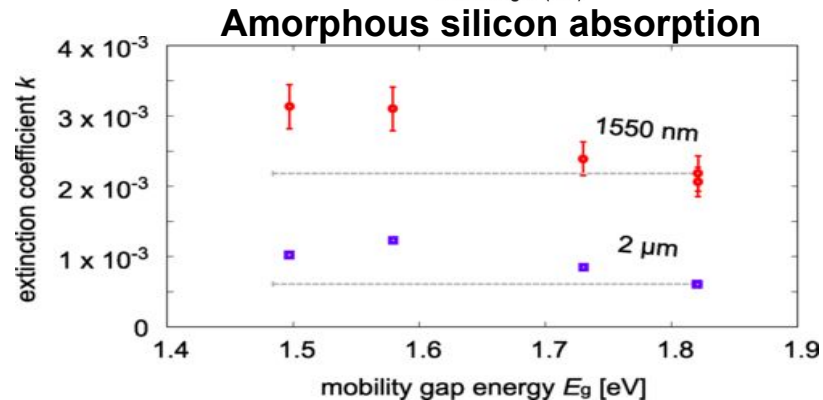
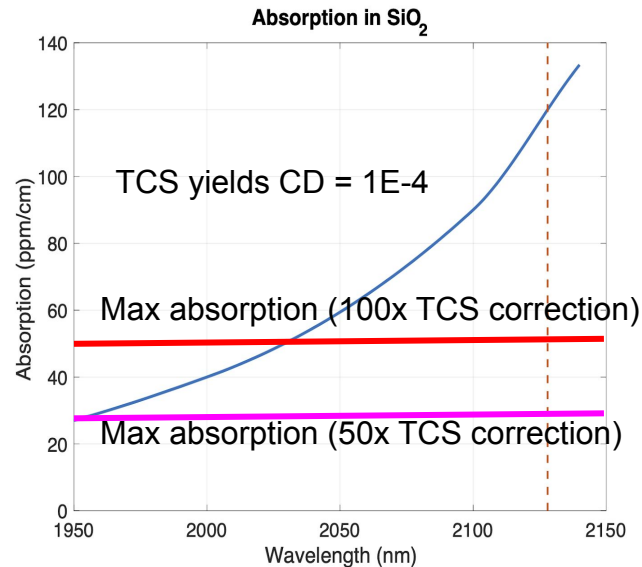
Motivation

- Current LIGO:
 - 1064 nm
 - Fused Silica Test Masses
- Silicon:
 - Cryogenic Compatible
 - Less Mechanical Loss / Thermal Noise
 - Opaque at 1064 nm



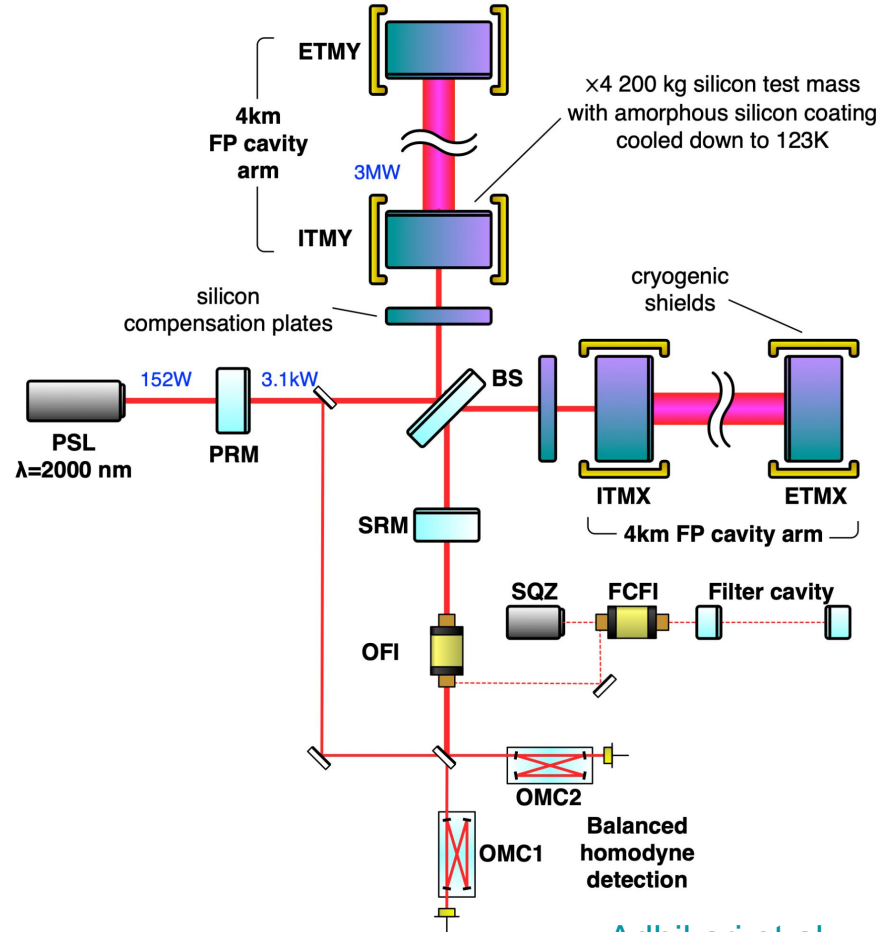
New Wavelength

- Low Si Absorption at 1400 - 2100 nm
- Current Laser Options:
 - 1550 nm
 - 1800 - 2100 nm
- Absorption Considerations:
 - Si has less absorption at longer wavelengths



LIGO Voyager

- Potential Post-O5 upgrade:
- Cryogenic Silicon Test Masses
- 2050 nm Wavelength
- Requires Stable 2050 nm Source



Laser Frequency Noise

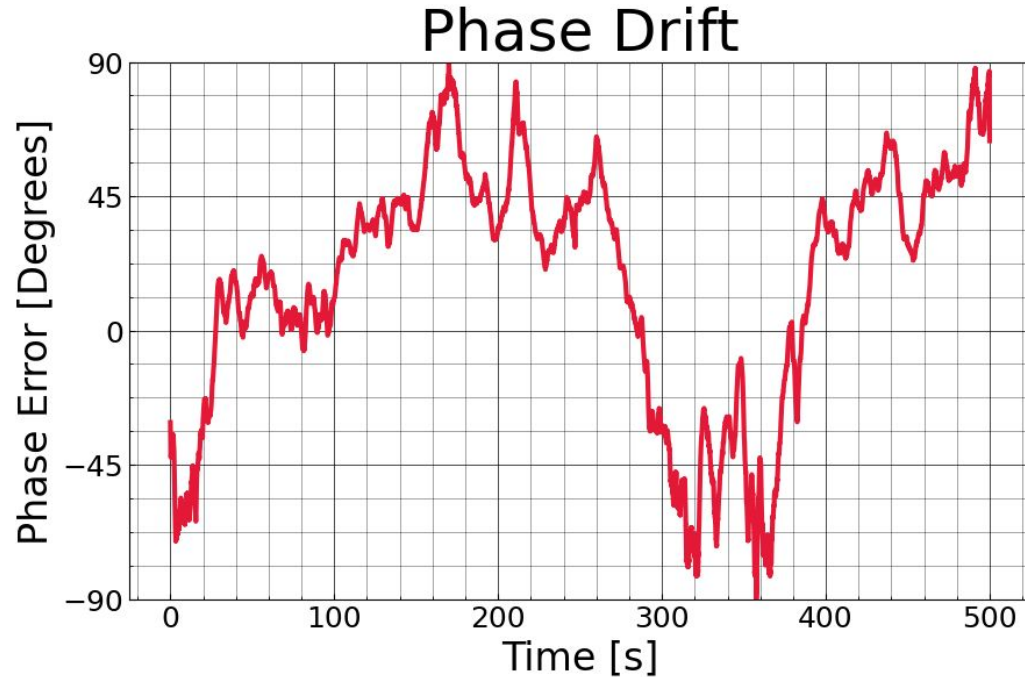
- Measure via Phase Noise:

$$2\pi f(t) = \omega(t) = \frac{d}{dt}\phi(t)$$

$$E(t) = Ae^{i(\omega_0 t + \phi_n(t))}$$

- Phase Forms a Random Walk
- Within Interferometer

$$\phi_n(t) = 2\pi f_n(t)\Delta t$$



Our Goals

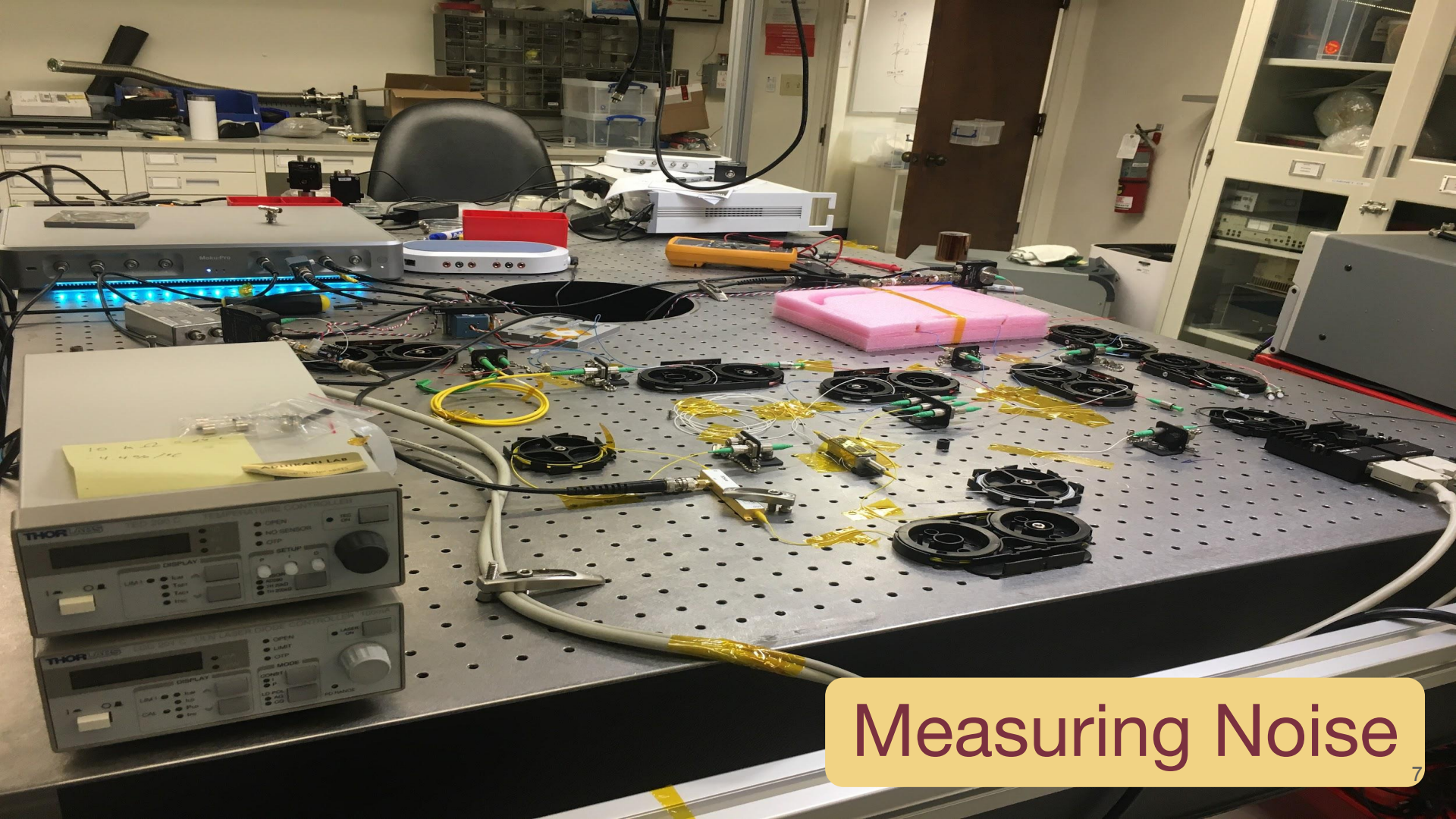
Measure Phase Error via Mach - Zehnder (MZ) Interferometer



Correct for Error via Feed Forward



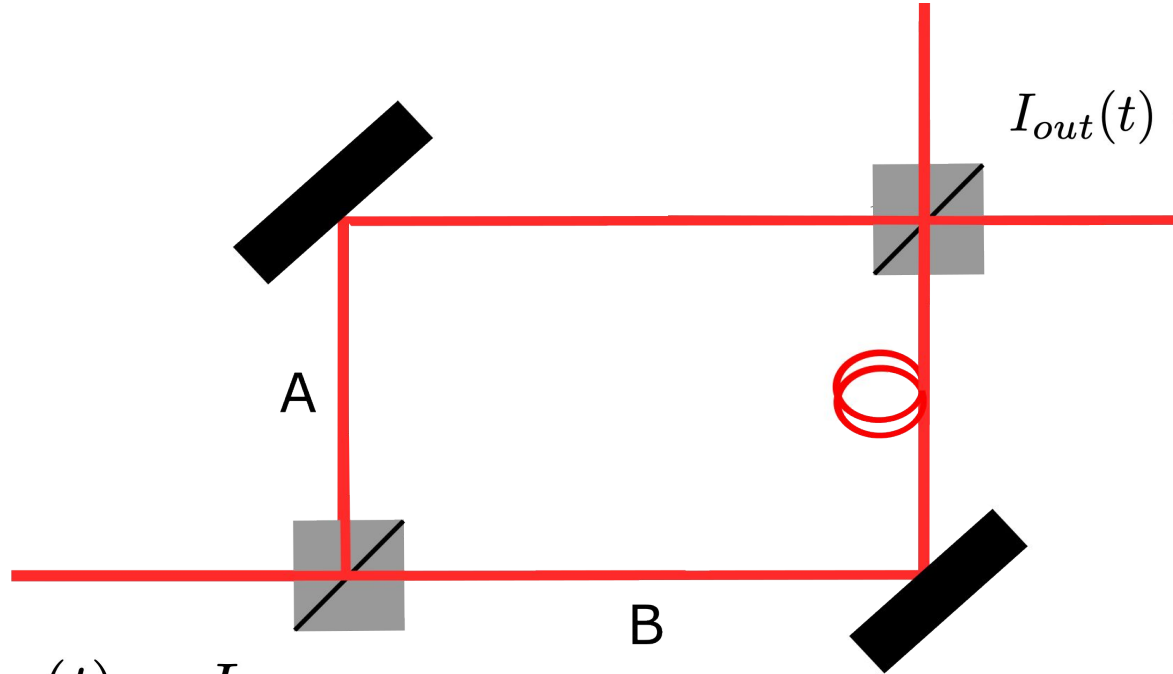
Measure Corrected Signal via Second MZ interferometer



Measuring Noise

Mach-Zehnder Interferometer

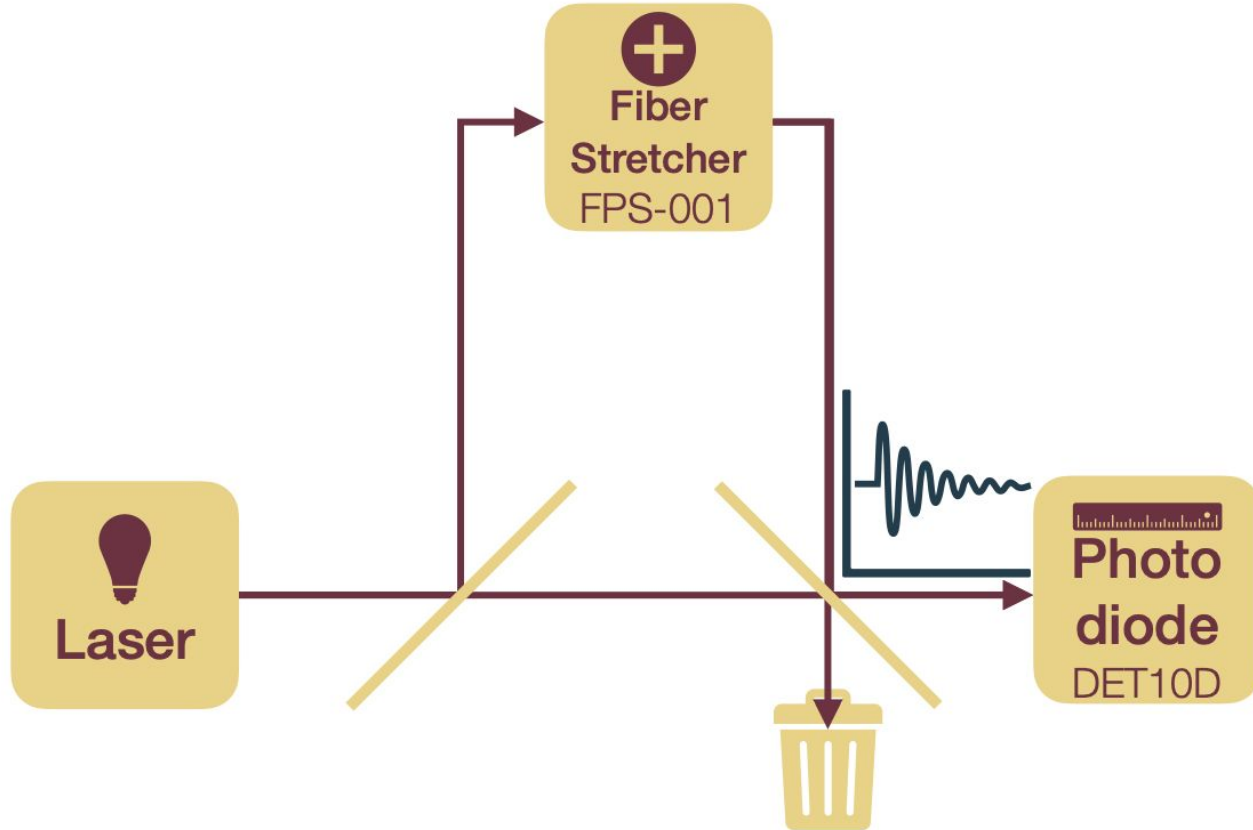
- Interferometer Arms Differ in Time Delay by τ .

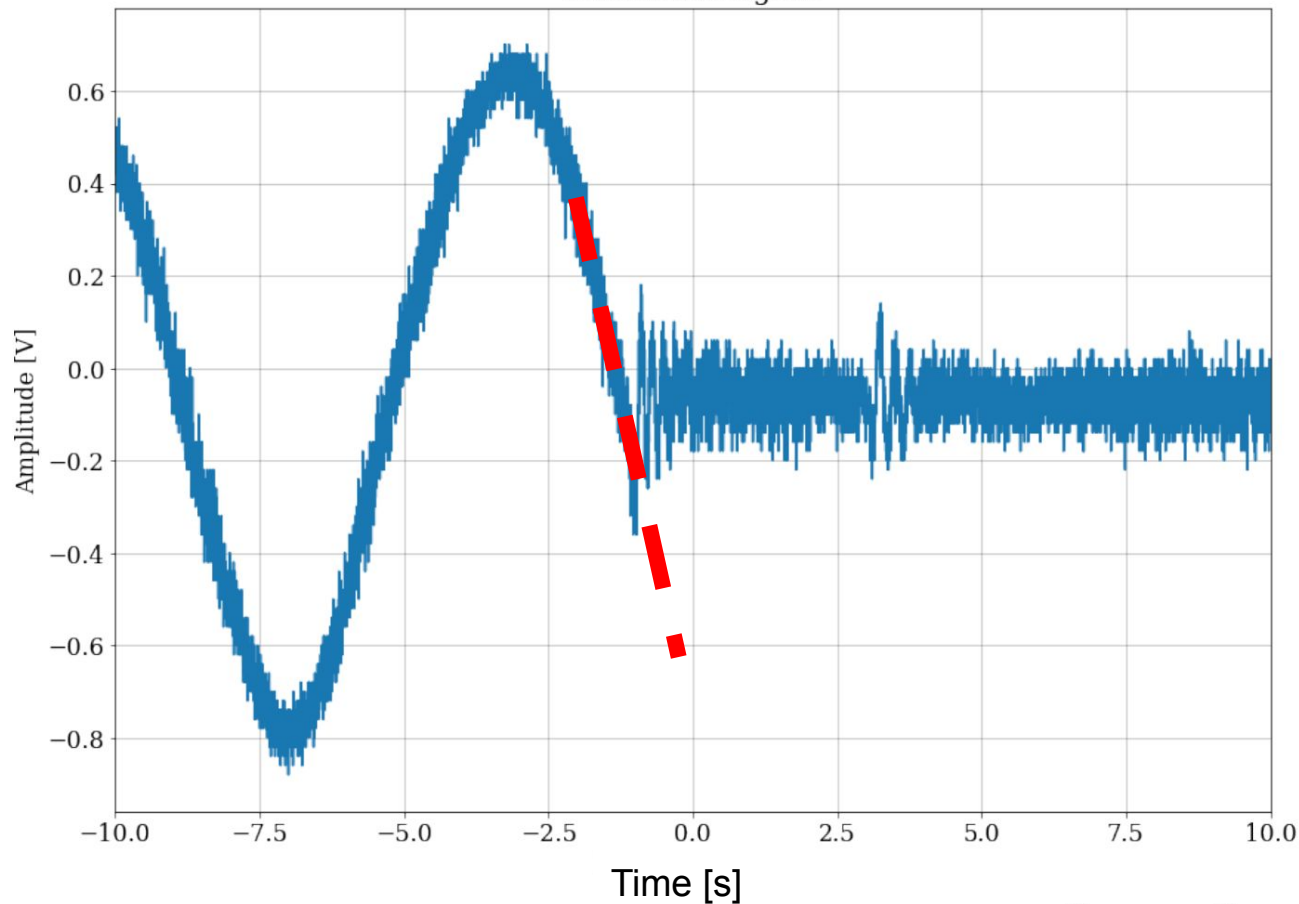


$$I_{out}(t) = \frac{I_0}{2} + \frac{I_0}{2} \sin(\underline{2\pi f_n(t)\tau} + \phi_0)$$

$$I_{in}(t) = I_0$$

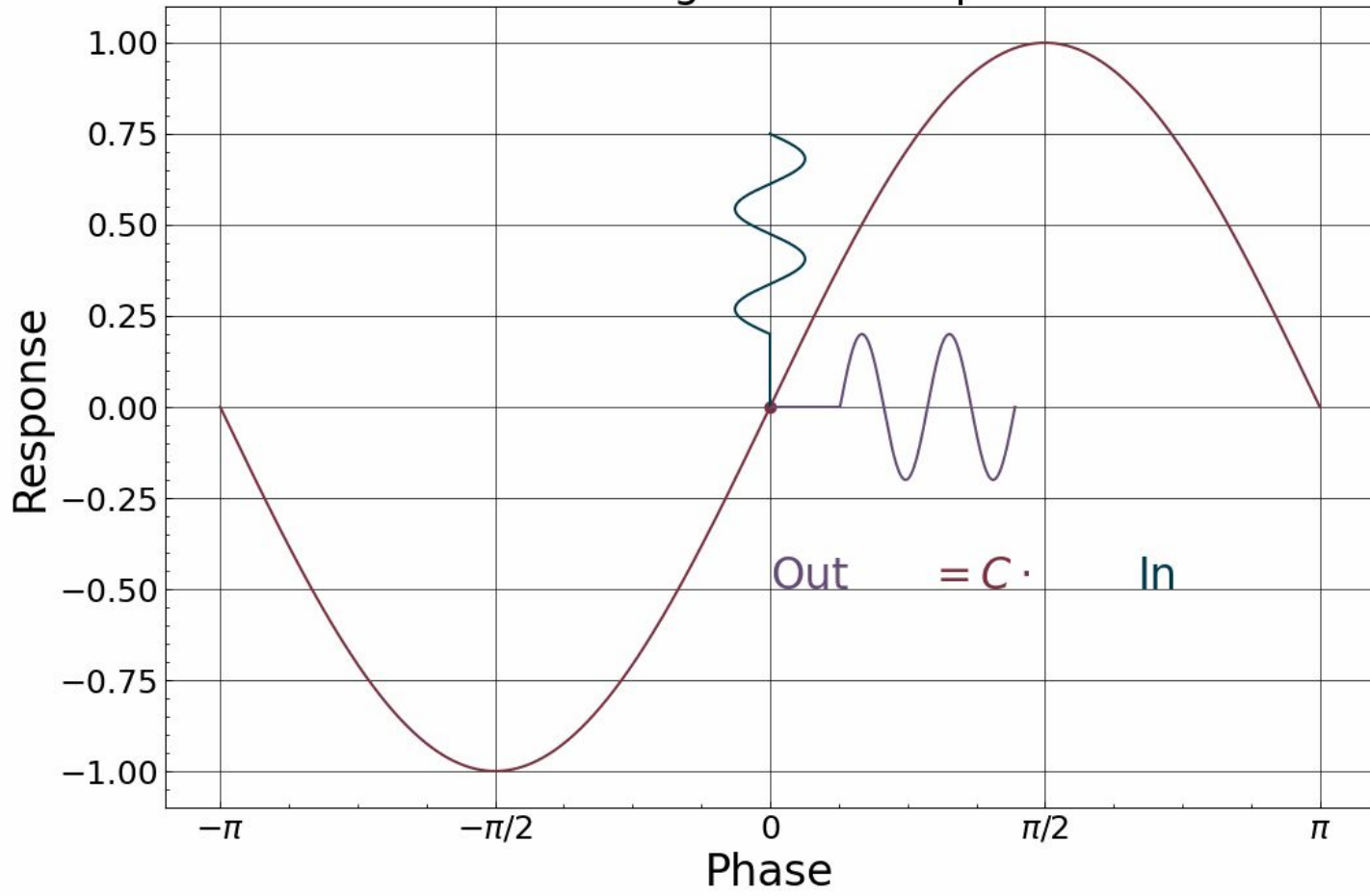
Fiber Stretcher Interferometer



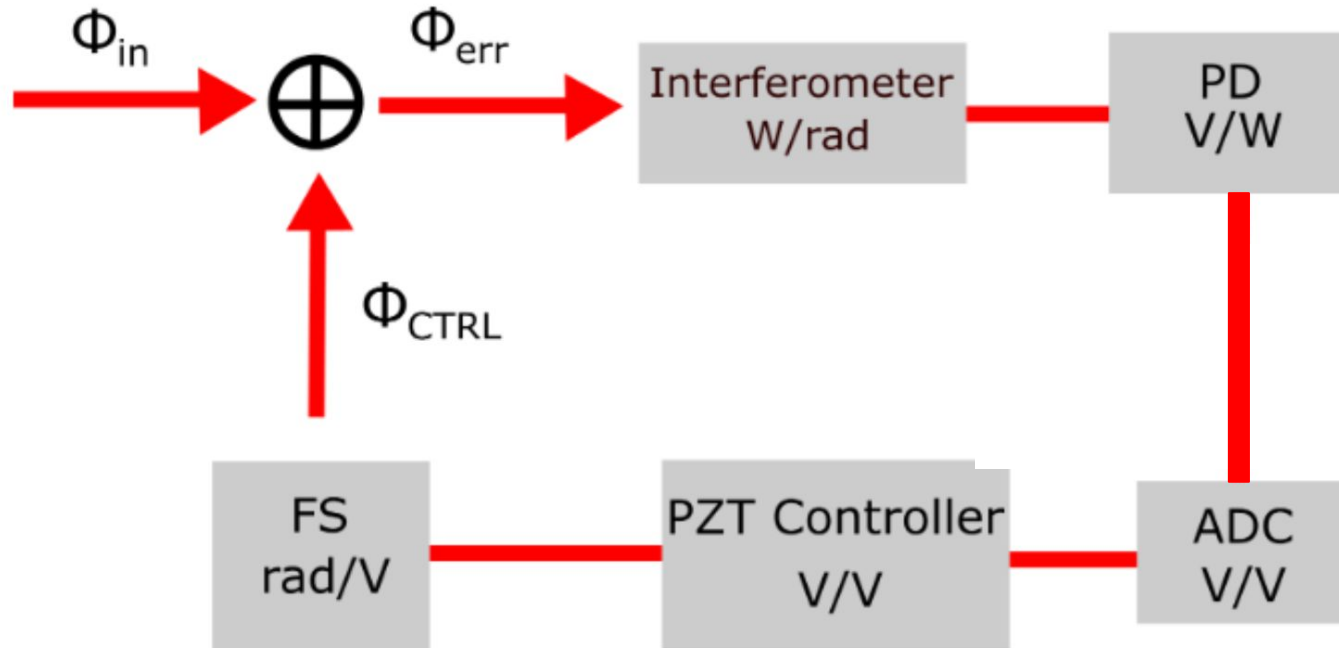


$$I_{out}(t) = \frac{I_0}{2} + \frac{I_0}{2} \sin(2\pi f_n(t)\tau + \phi_0) \longrightarrow I_{out}(t) = \frac{I_0}{2} + \frac{I_0}{2} 2\pi f_n(t)\tau$$

Measuring Around Setpoint



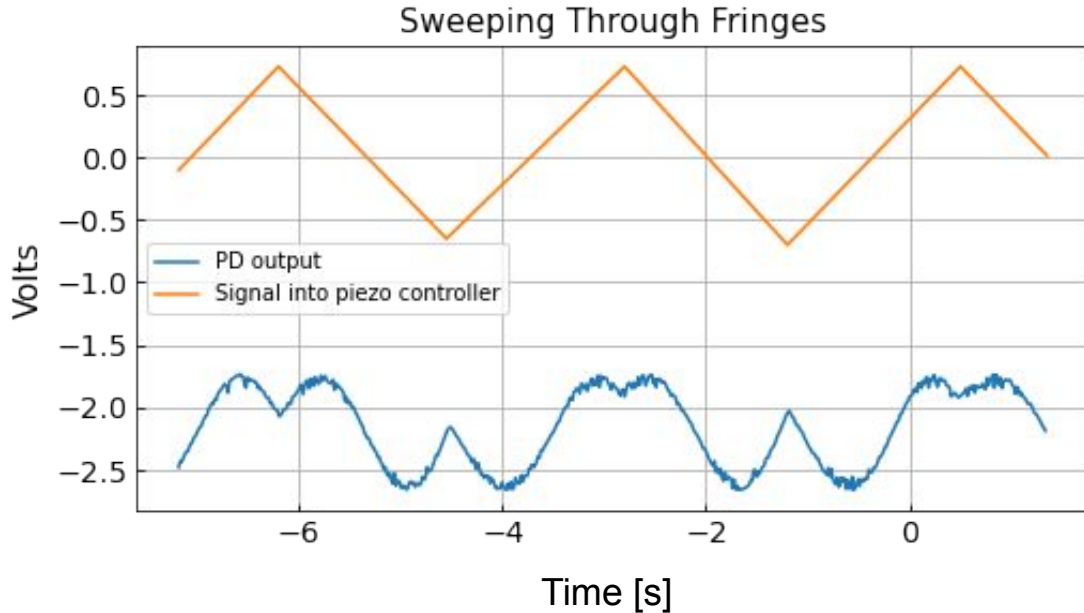
Locking the Loop



Calibrating Noise

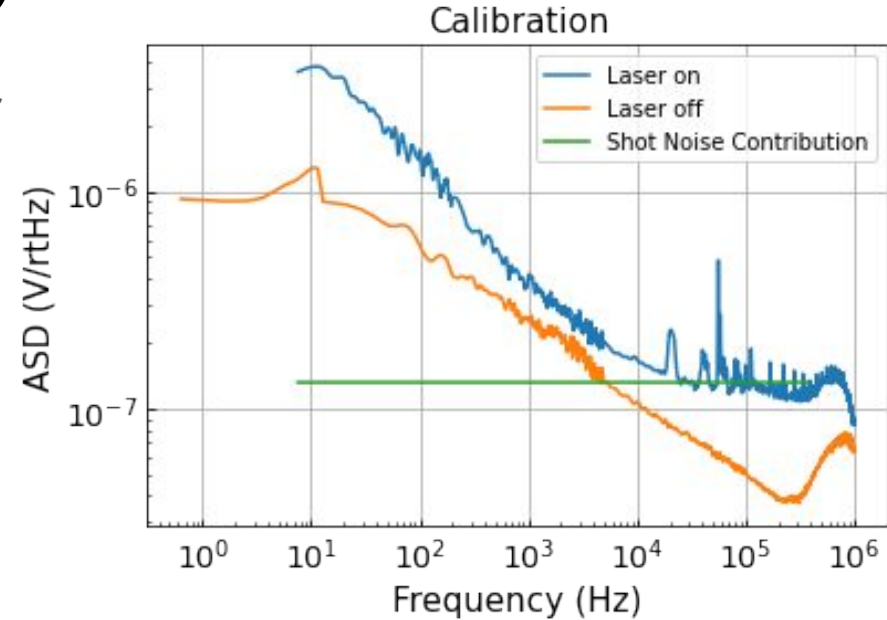
- Sweep through fringes with fiber stretcher to correlate input voltage out of PD with radian change $\frac{\text{radians}}{\text{volt}}$
- Radian change and frequency drift related by

$$f(t) = V_{out}(t) \frac{\text{radians}}{\text{volt}} \frac{1}{2\pi\tau}$$



Calibrating the Photodiode (PD)

- Correspond PD Voltage to Laser Power
- Low Frequencies:
 - 1/f Intensity Noise Dominates
- High Frequencies:
 - Shot Noise Dominates
- Variations in Electron Flow
- ASD of Shot Noise in amps/rHz Given by $\delta n_{shot} = \sqrt{2q|\bar{I}|}$



Noise Sources

- Moku Input Noise floor
- Shot noise
- Photodiode Dark Noise
- Relative Intensity Noise
- Frequency Noise
- Piezo Controller Noise
- Moku Output Noise



Image credit:
[Photonics Media](#)



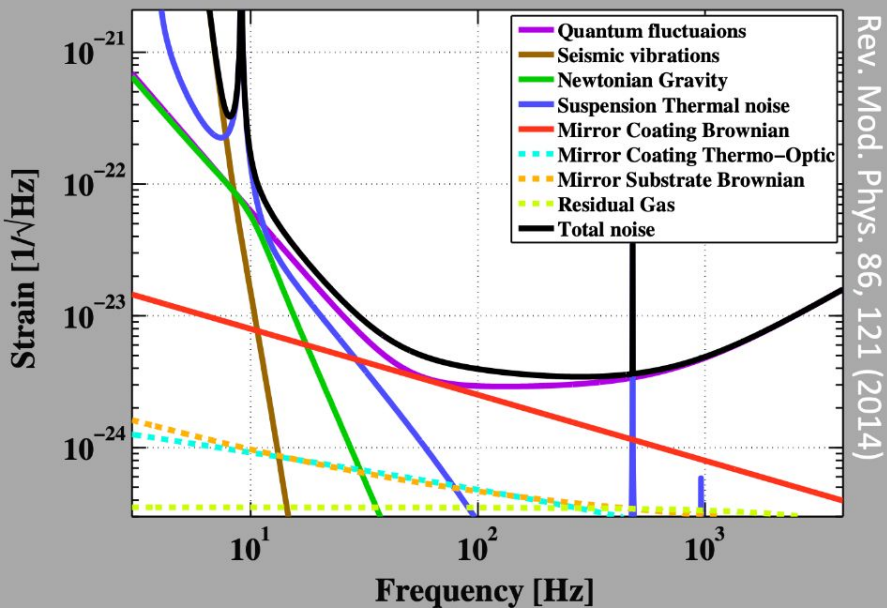
Image credit:
[Thorlabs](#)



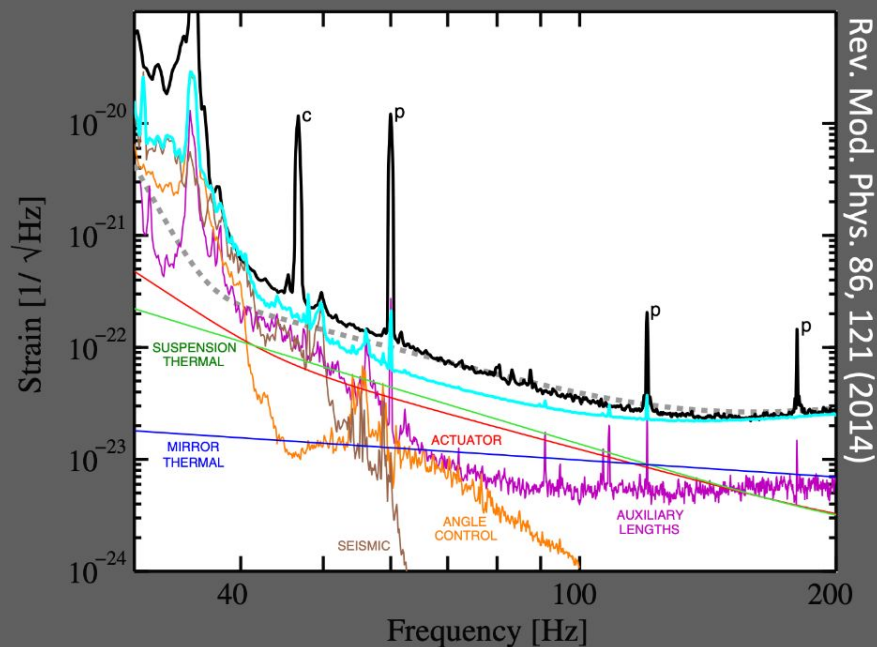
Image credit:
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LIGO Noise Budget

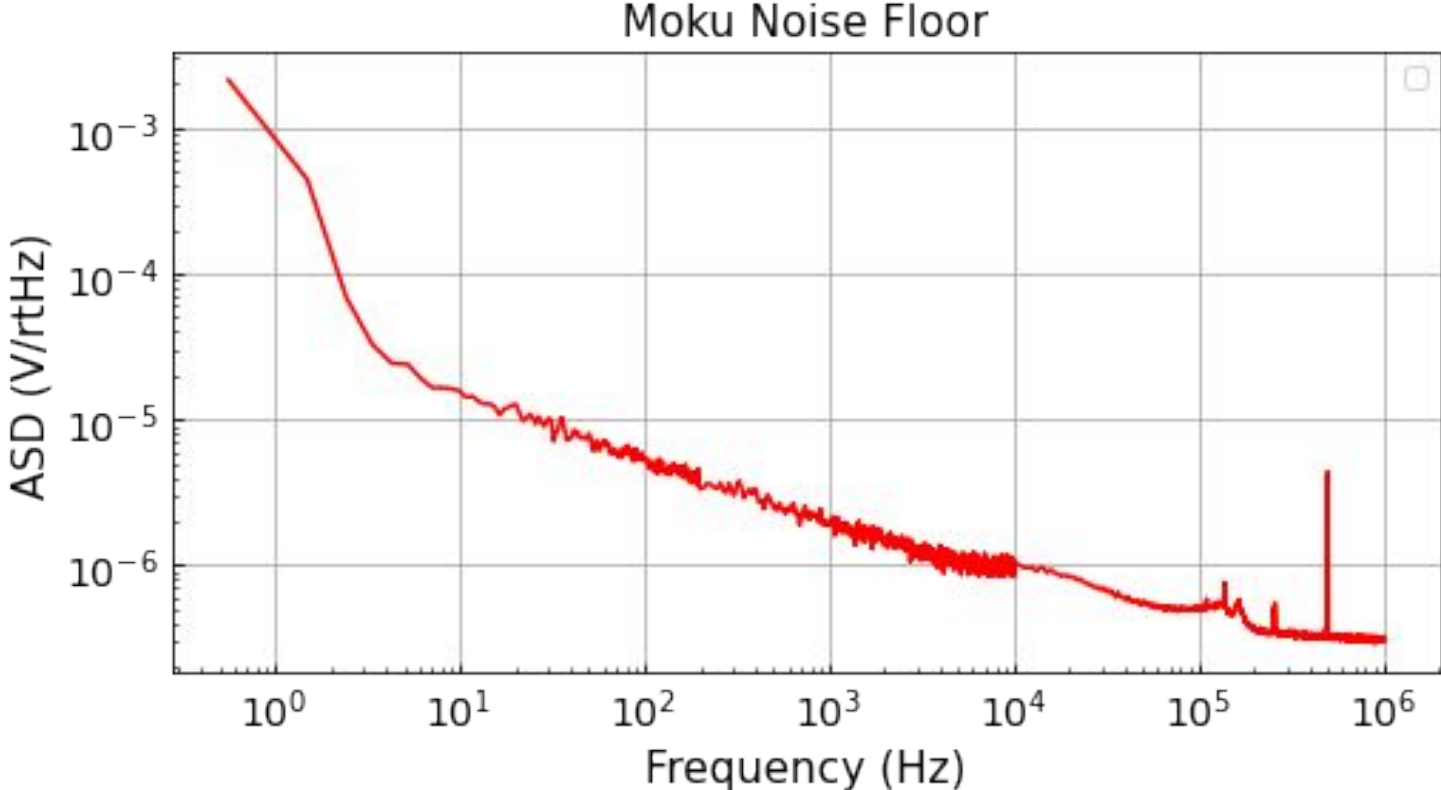
Theoretical Noise Budget



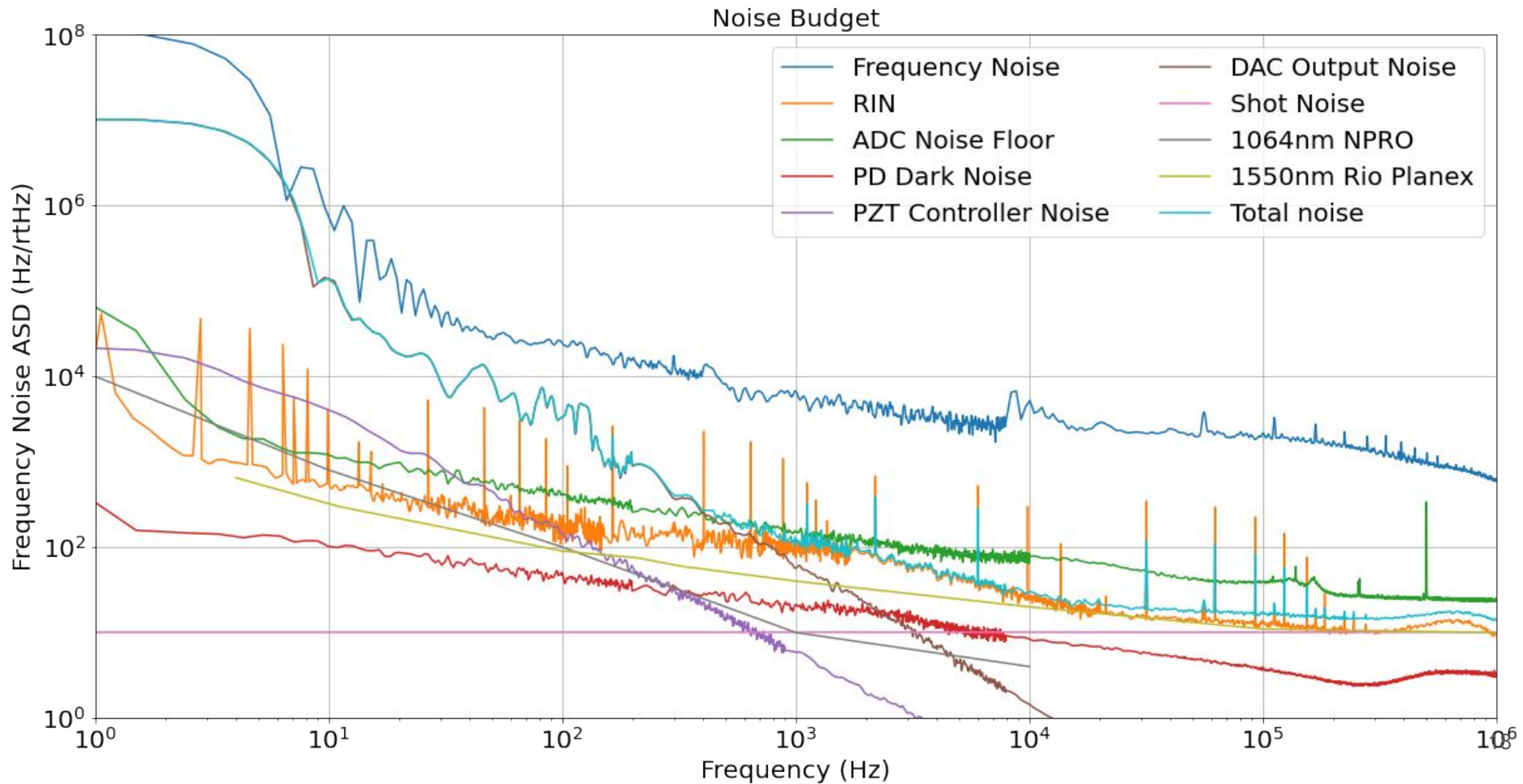
Realistic Noise Budget

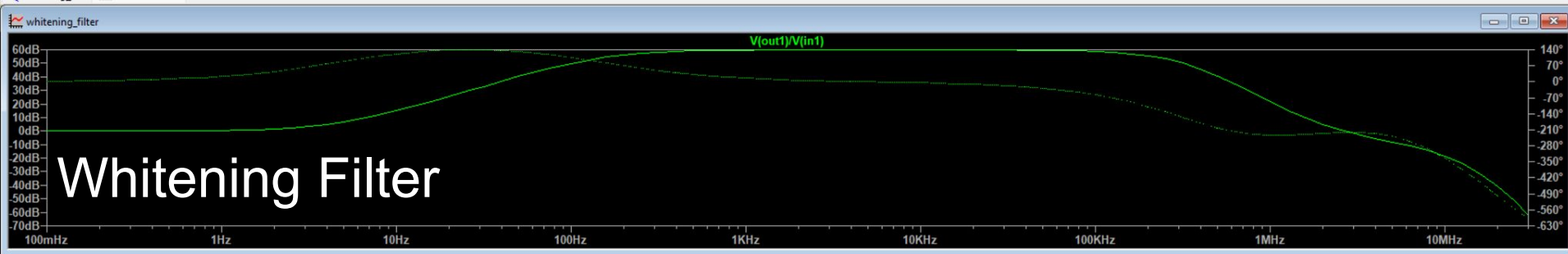


Moku Input Noise Floor

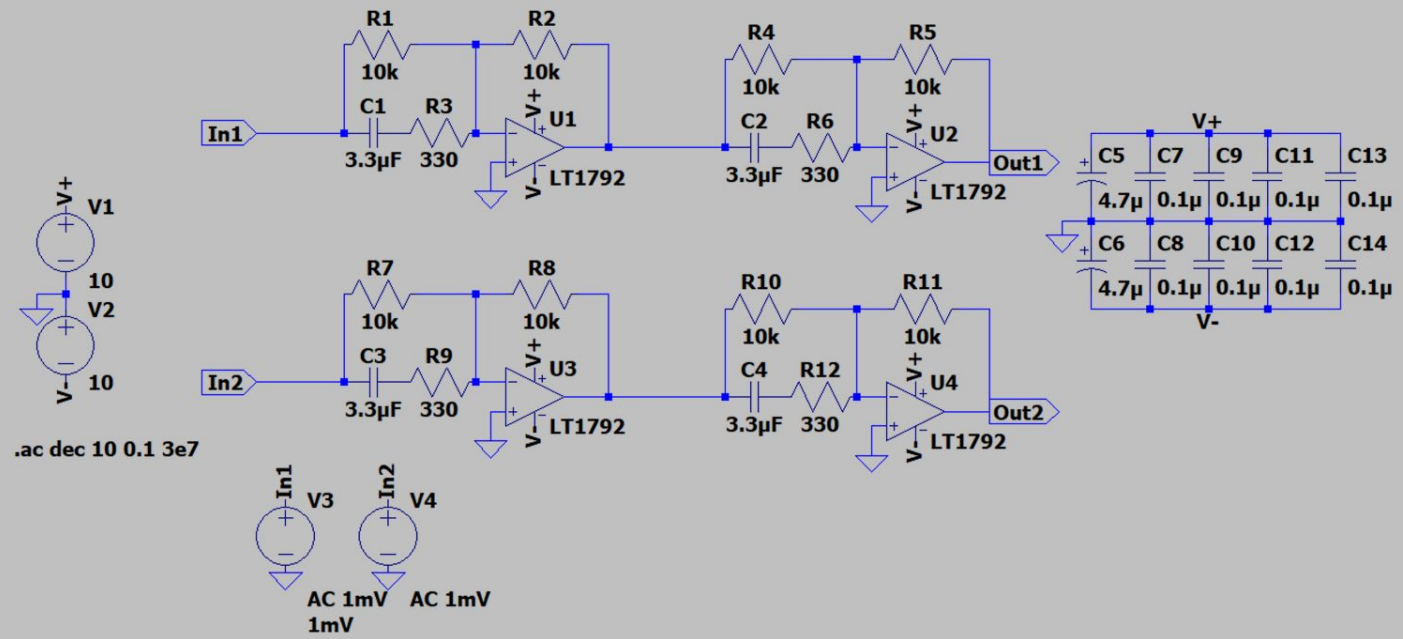


Noise Budget Before Whitening

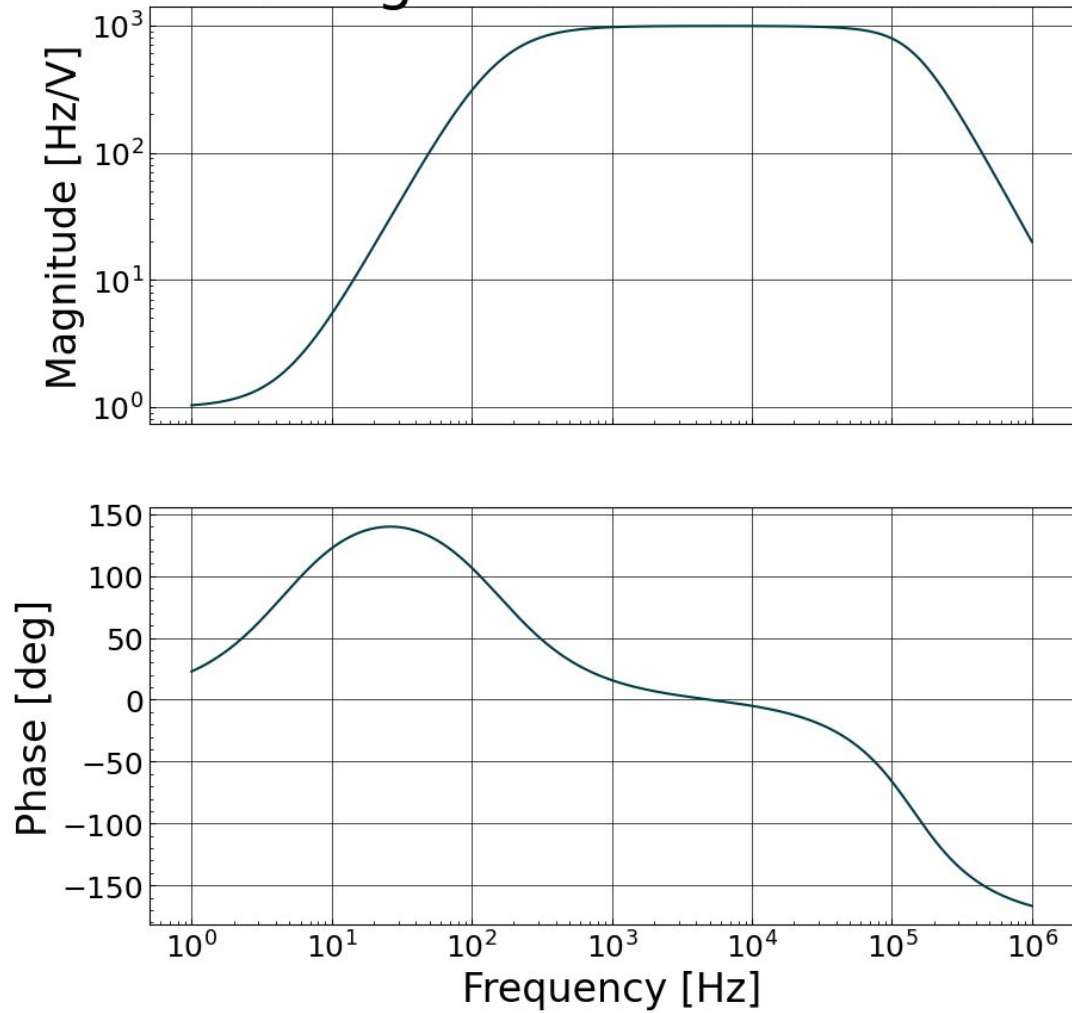




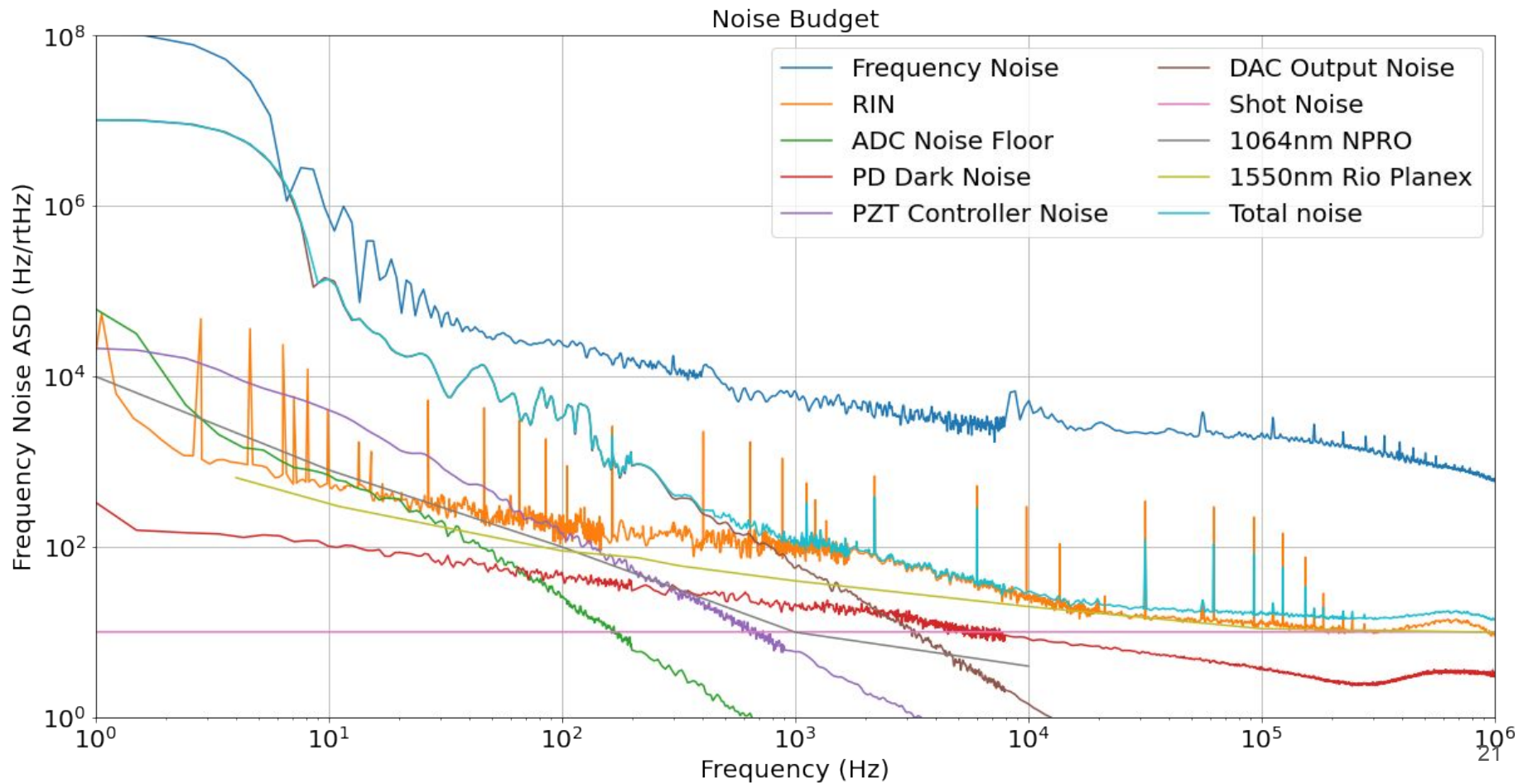
Whitening Filter



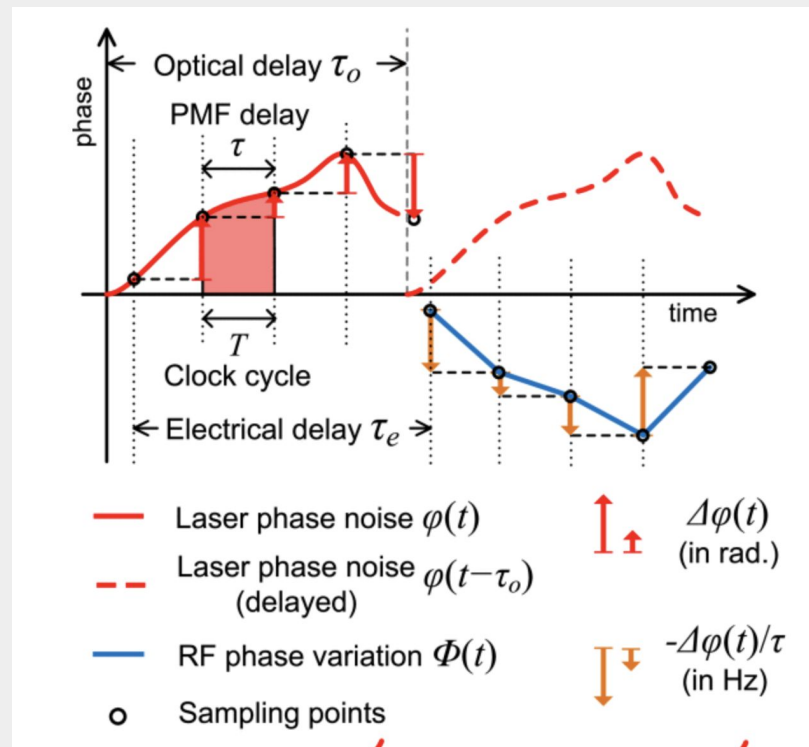
Whitening Filter Transfer Function



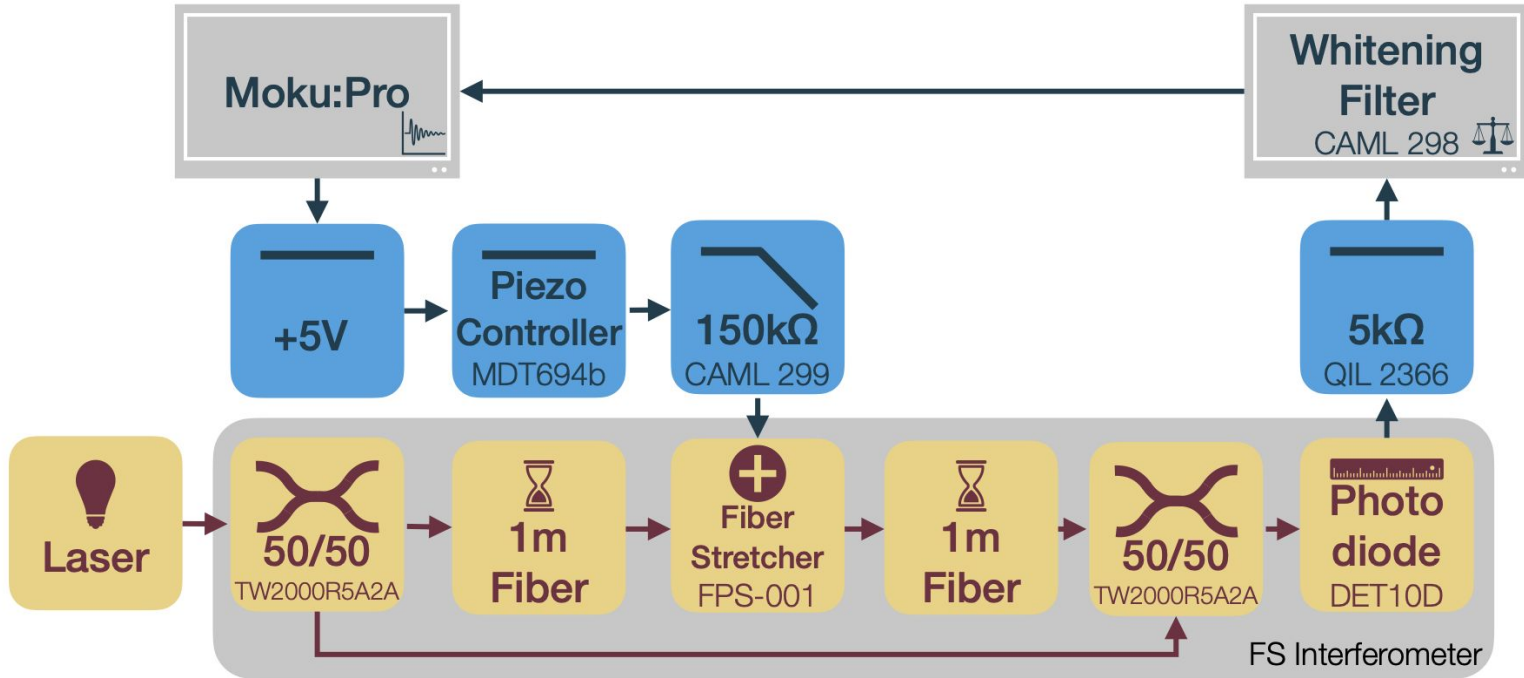
Noise Budget After Whitening



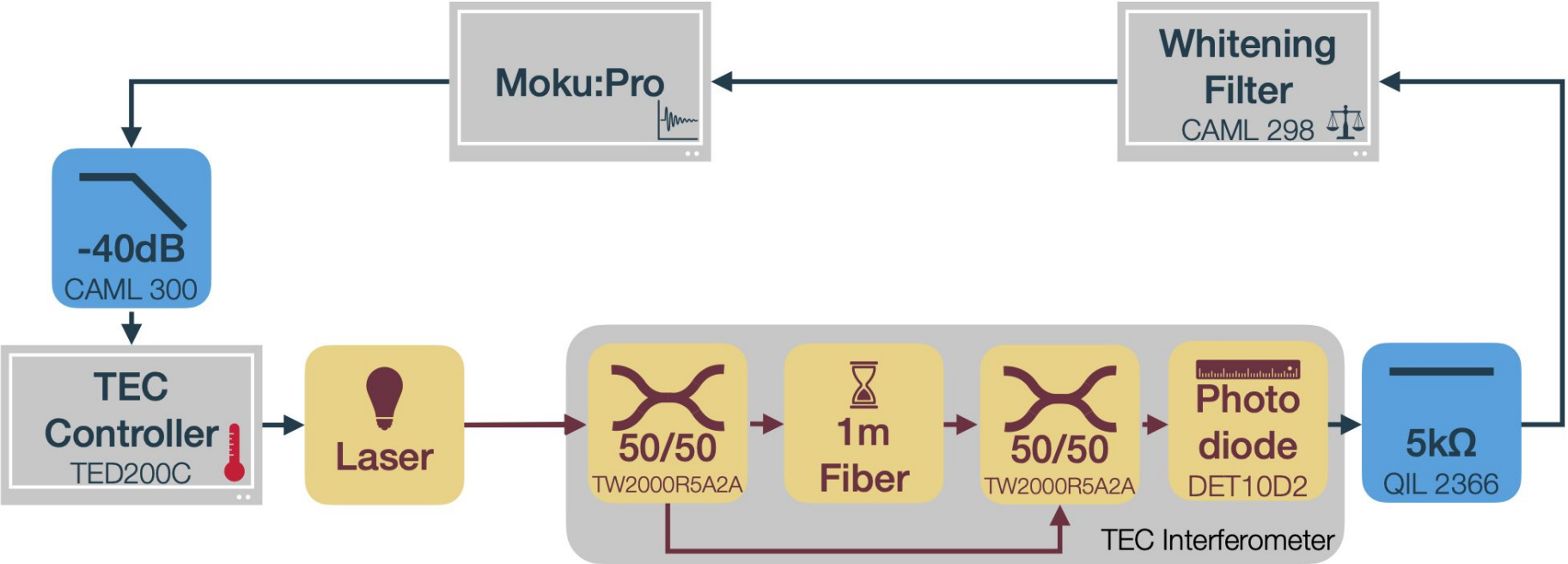
Performing the Feedforward



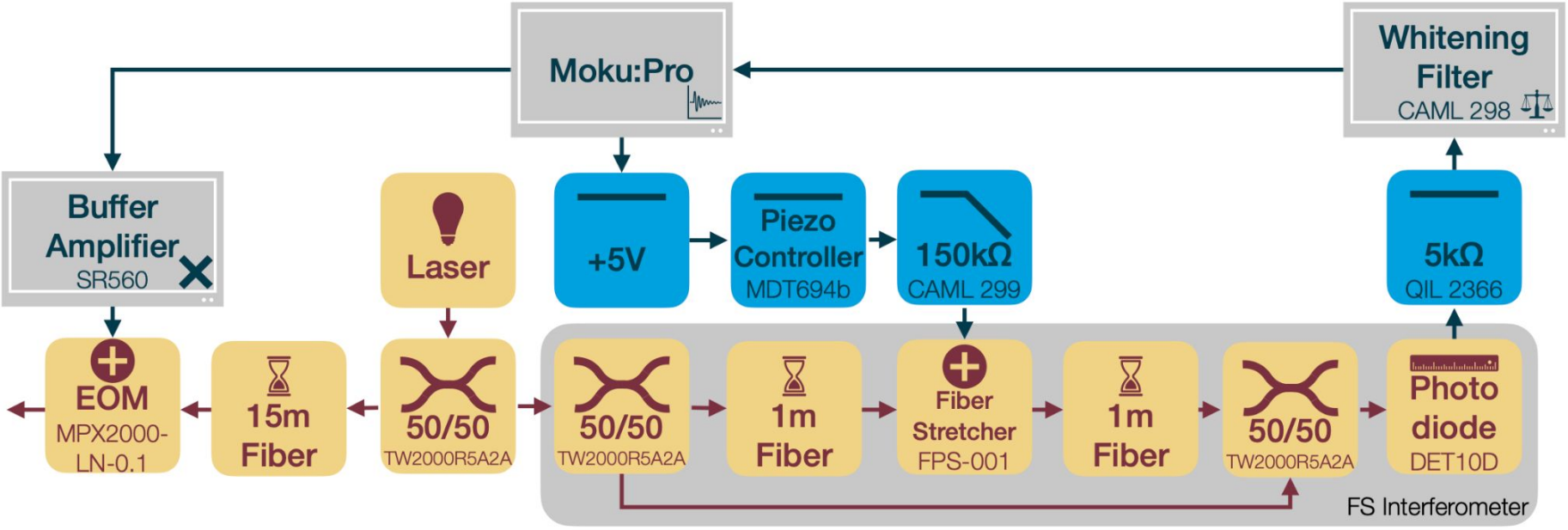
Block Diagram



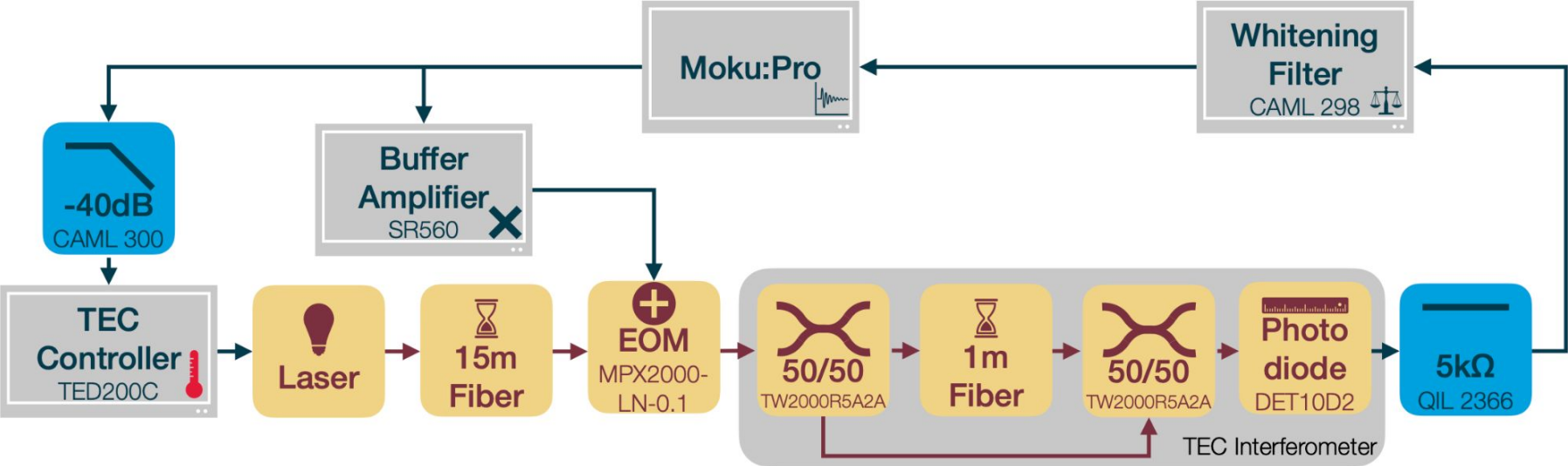
Block Diagram



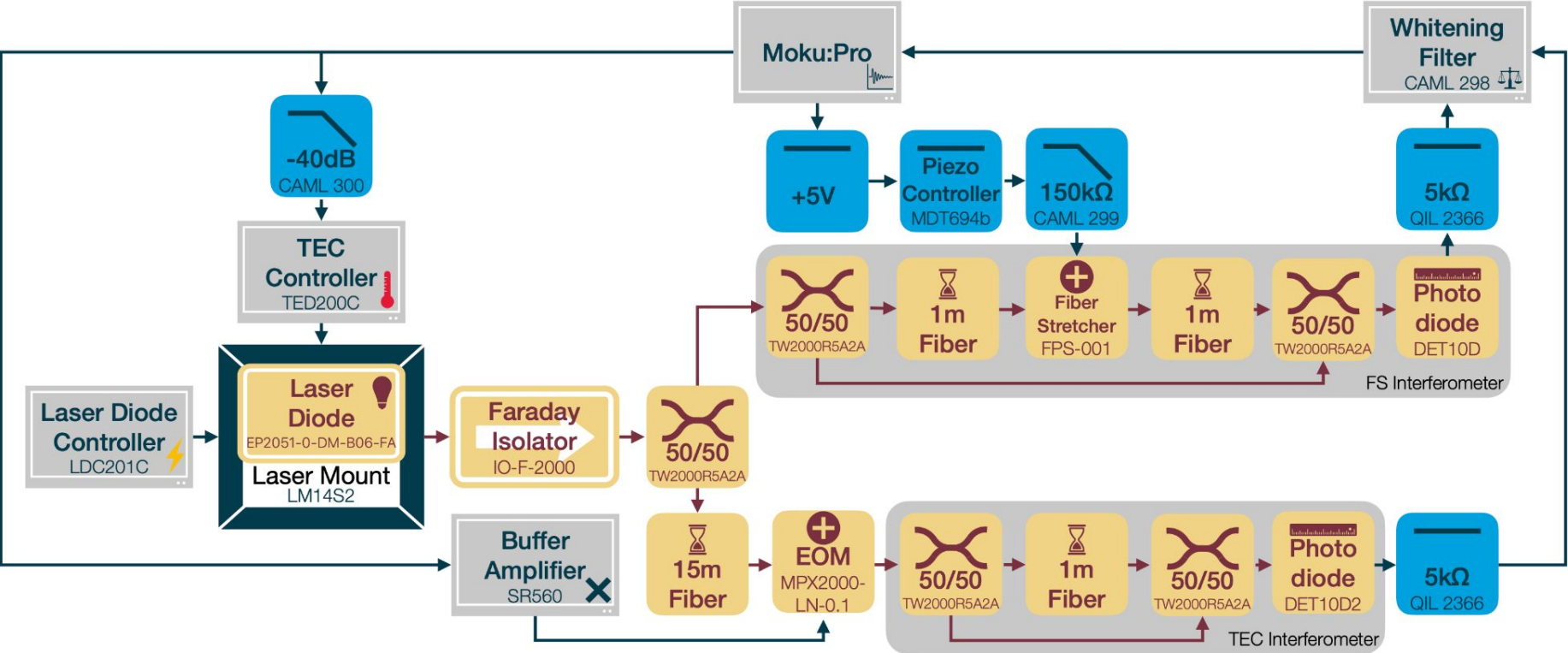
Block Diagram



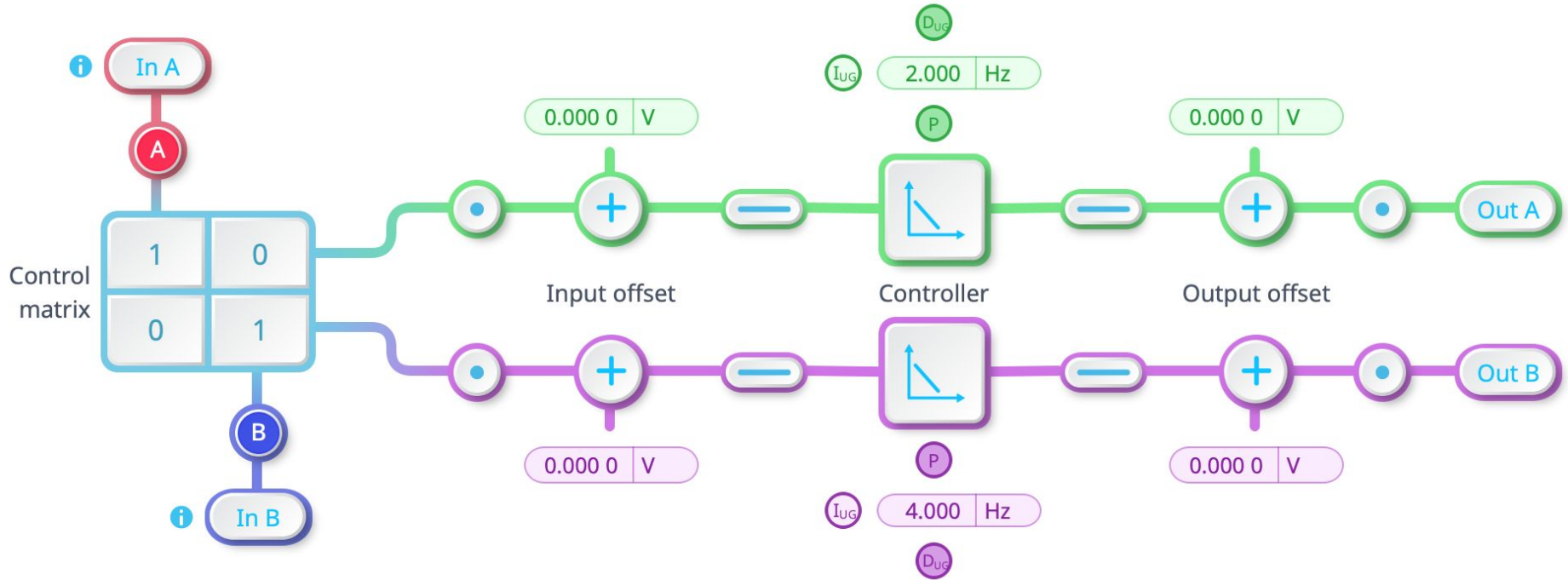
Block Diagram



Block Diagram

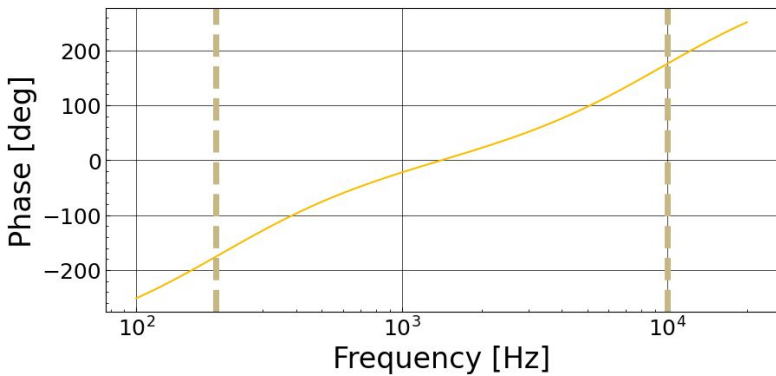
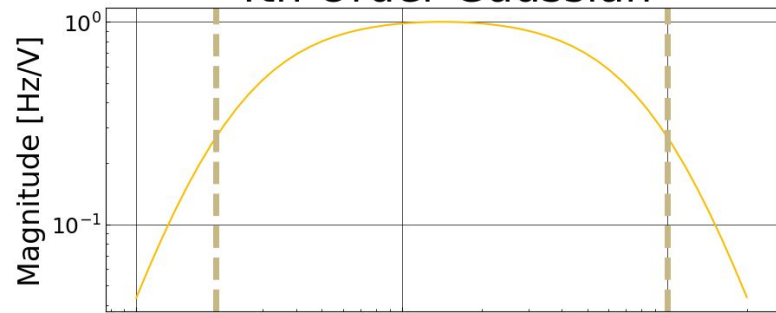


Locking Both Interferometers

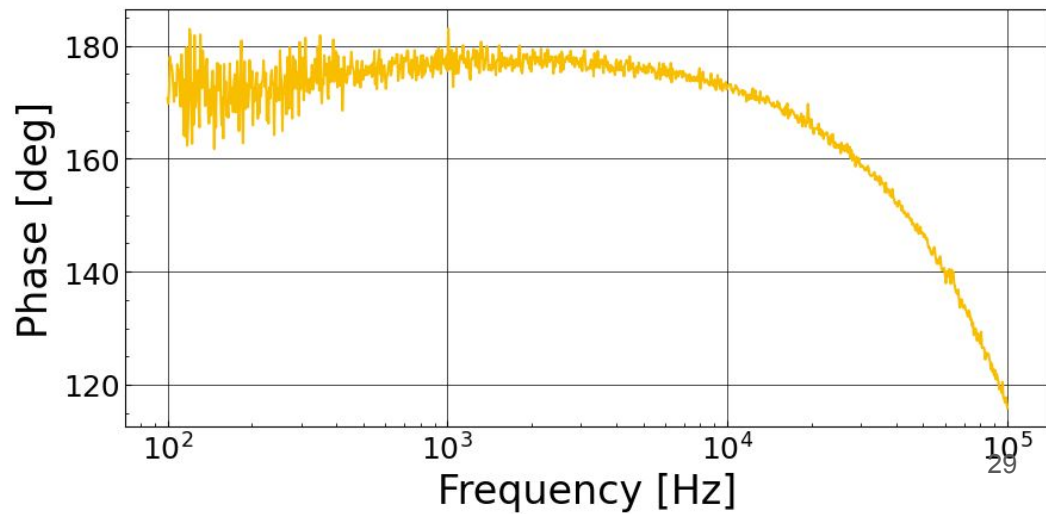
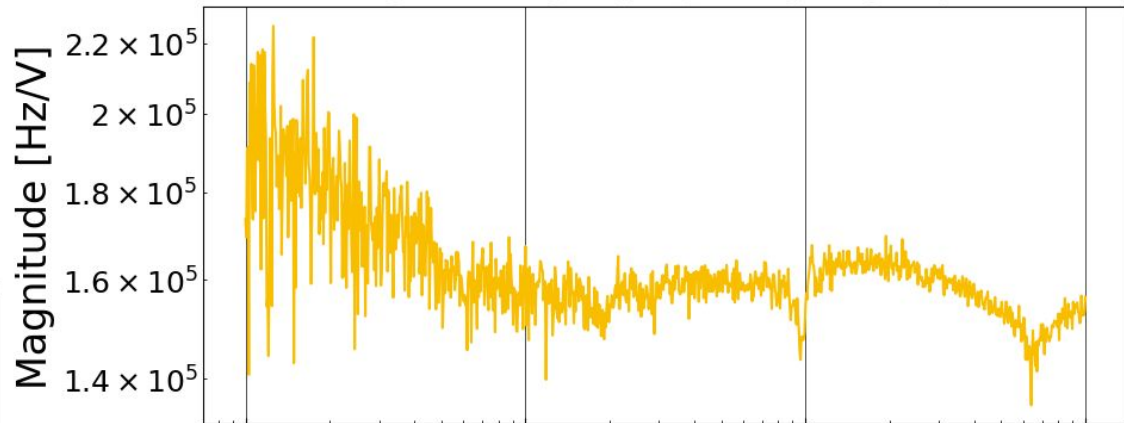


Controlling EOM

4th Order Gaussian

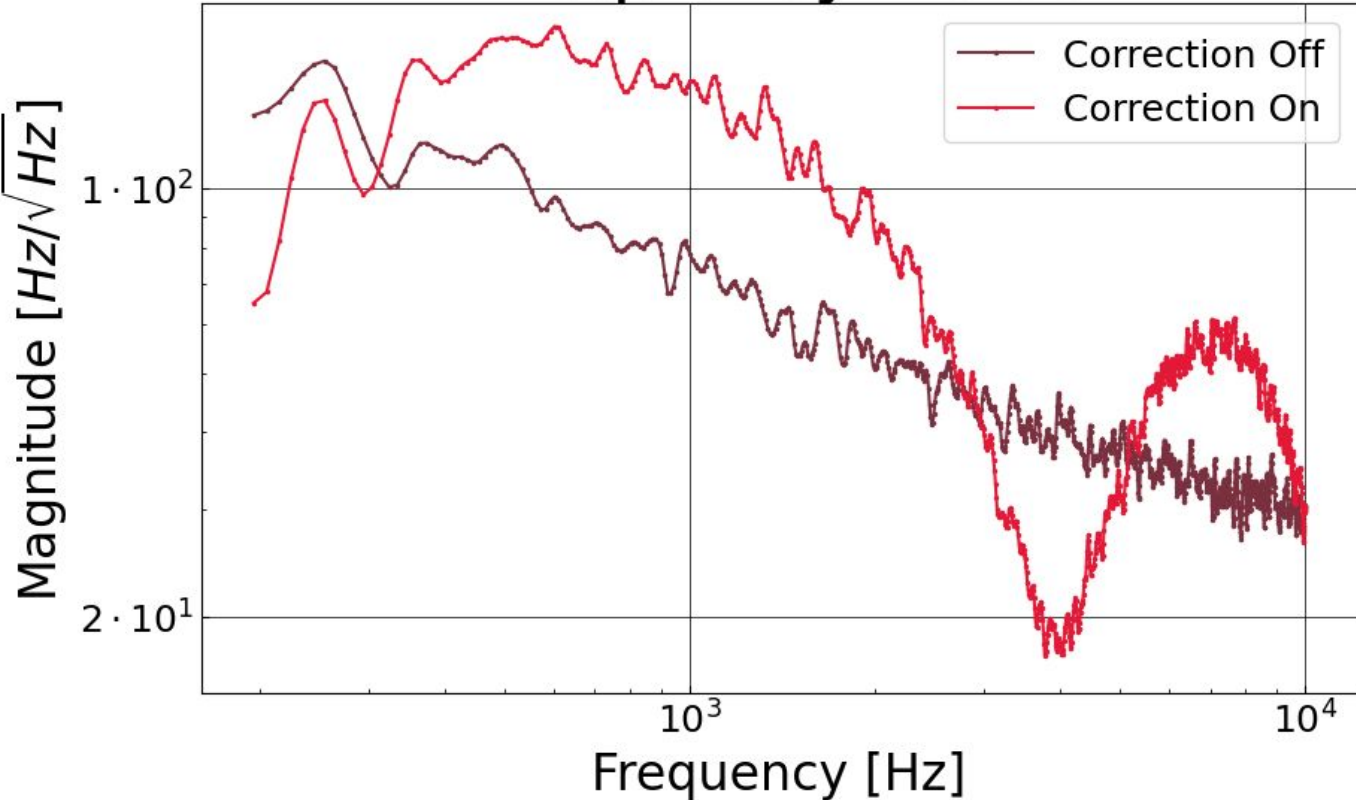


EOM Transfer Function



Demonstration of Noise Reduction

Frequency Noise



Conclusions

Successes:

- Two Interferometers
- Analysis of Noise in Measurement
- Demonstration of Noise Reduction

Future Work:

- Continue Modeling System
 - Analytic Ideal Cancellation
- Extend Cancellation Range
- Match Electrical & Optical Delay

Acknowledgements

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National Science Foundation

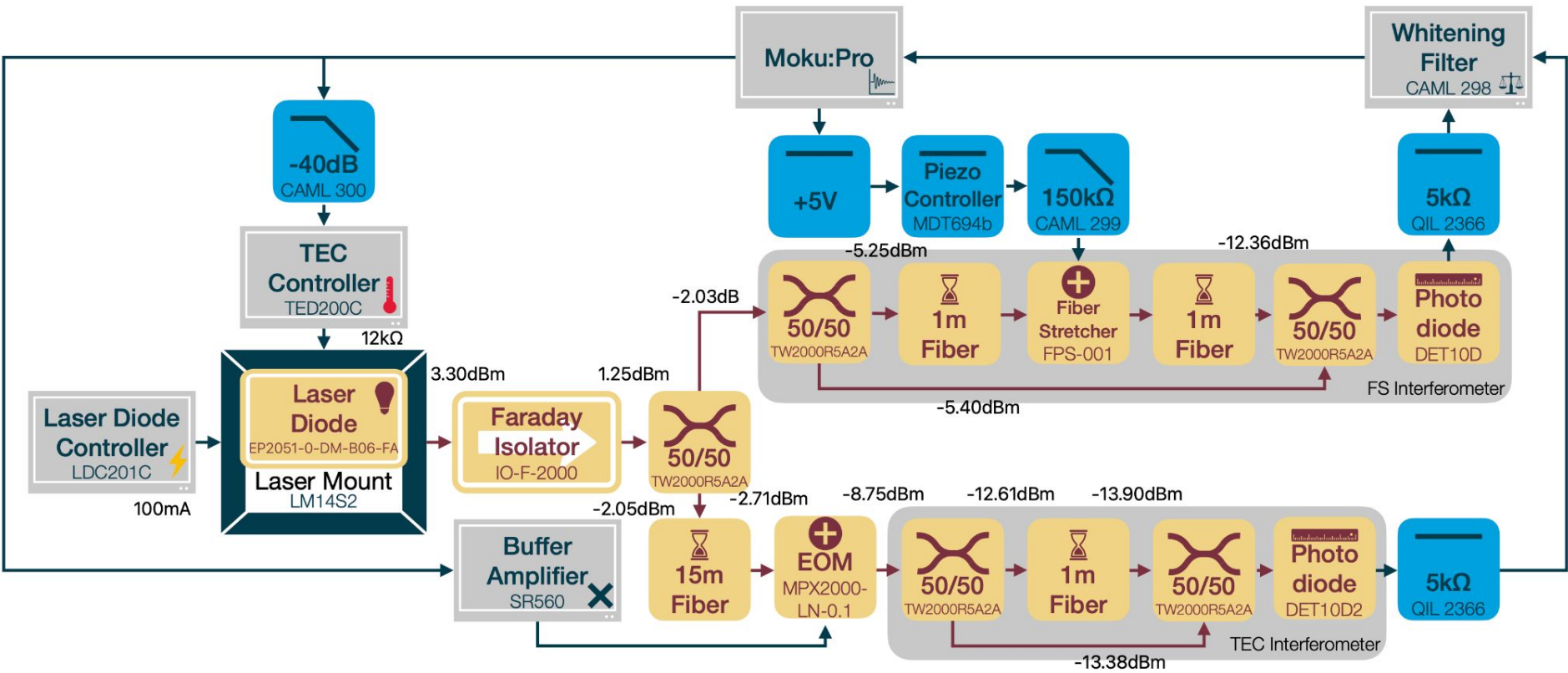
Caltech Class of '52 Named SURF

Caltech SFP Office

All the LIGO SURF students!

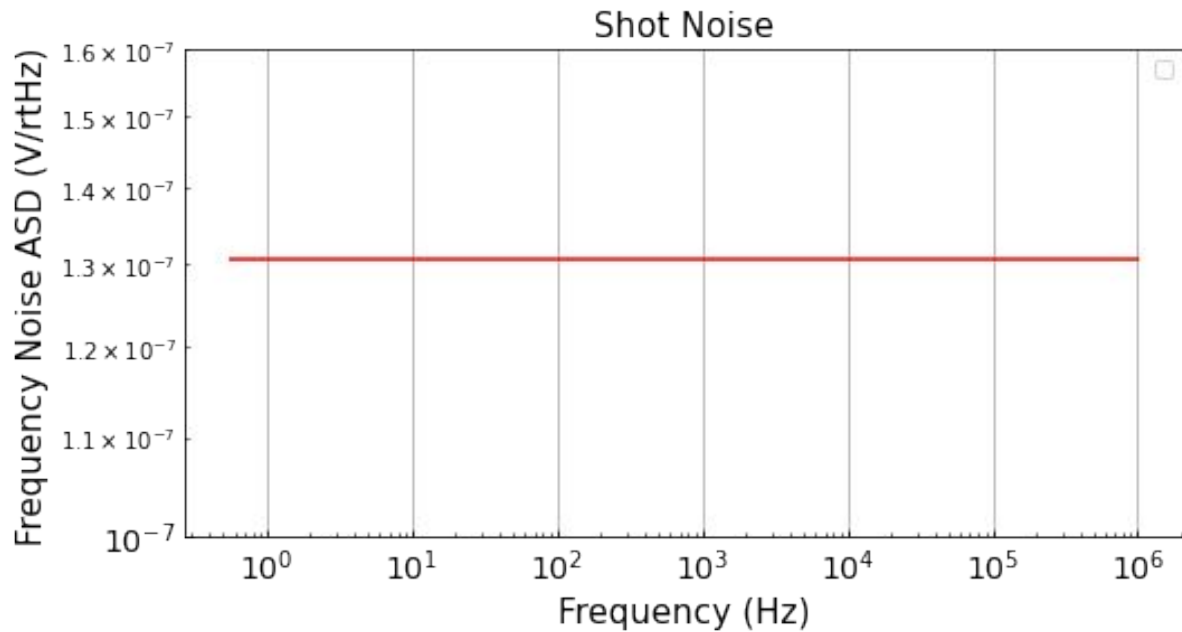


Extra Slides



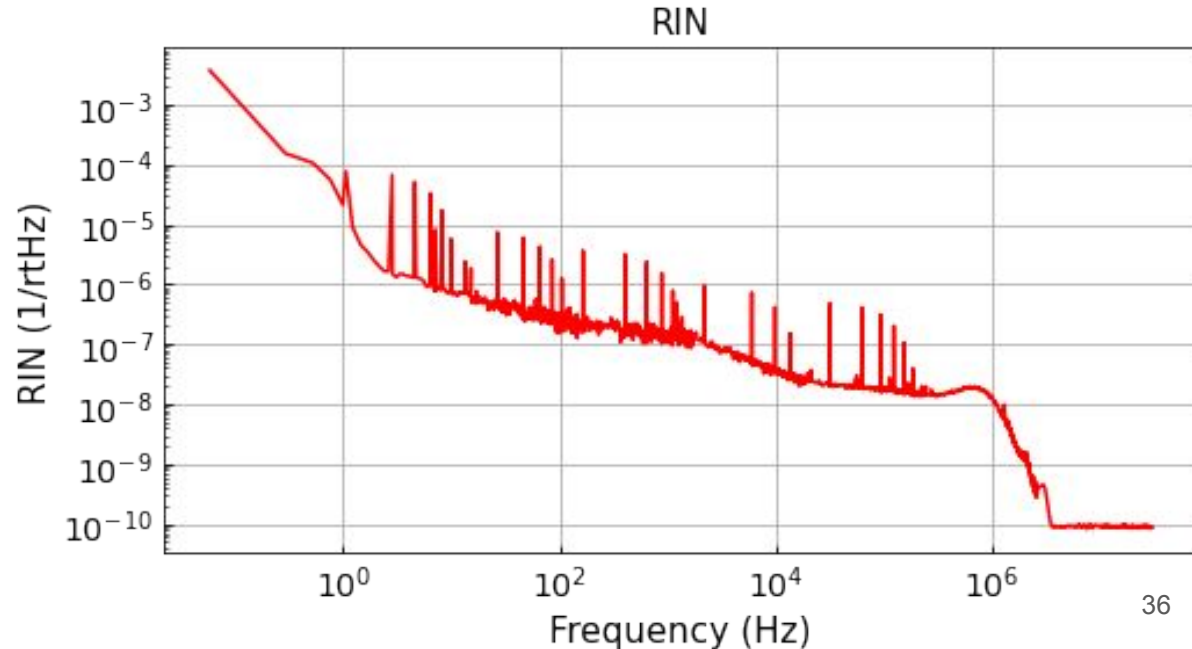
Shot Noise

- Noise due to the fact that photocurrent is a discrete flow of electrons
- There are variations in electron flow, as governed by Poisson statistics
- ASD of shot noise in amps/rHz given by $\delta n_{shot} = \sqrt{2q|\bar{I}|}$
 - q : charge of electron
 - $|\bar{I}|$: absolute value of average current



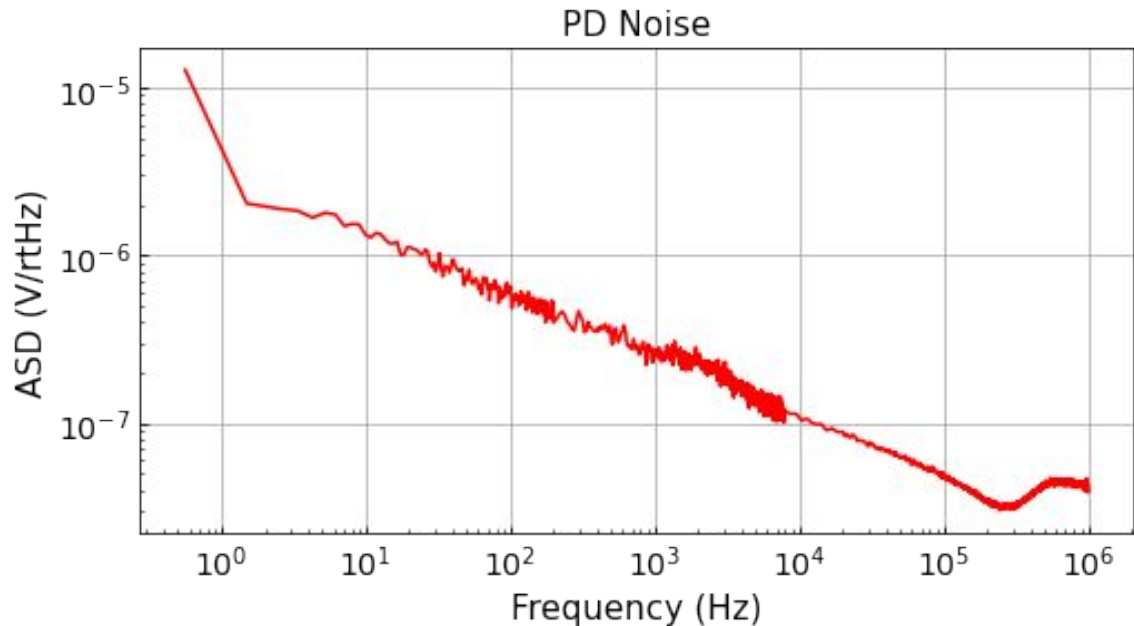
Relative Intensity Noise

- Fluctuations in intensity of laser output
- Measured without interferometer
- Convert input wattage of measured signal into DC output voltage, divide spectrum by this DC value



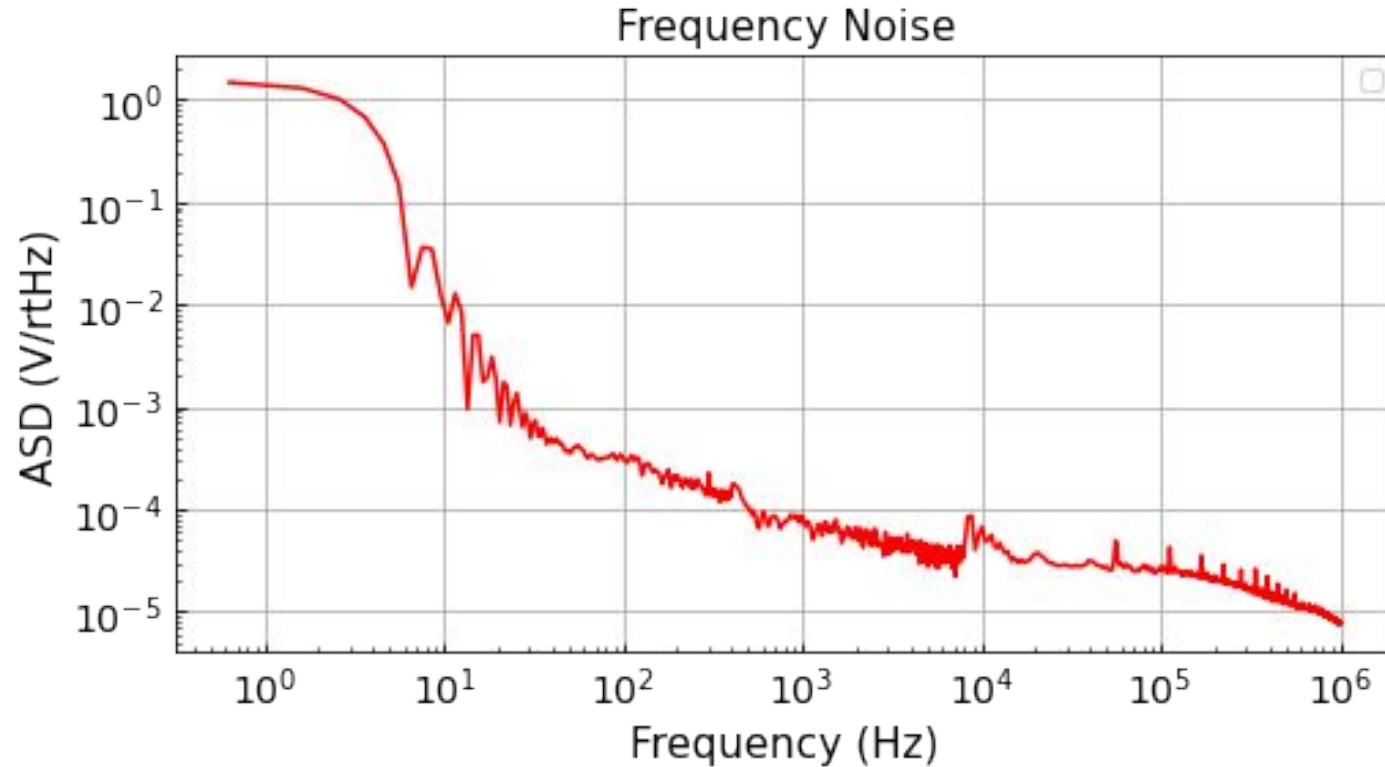
Photodiode Noise

- “Dark noise” from applying DC bias to diode
- Present whether laser is on or off
- Can't just measure signal out of PD since it is below ADC noise floor
- Measured with signal amplified, then undid the amplification in our analysis



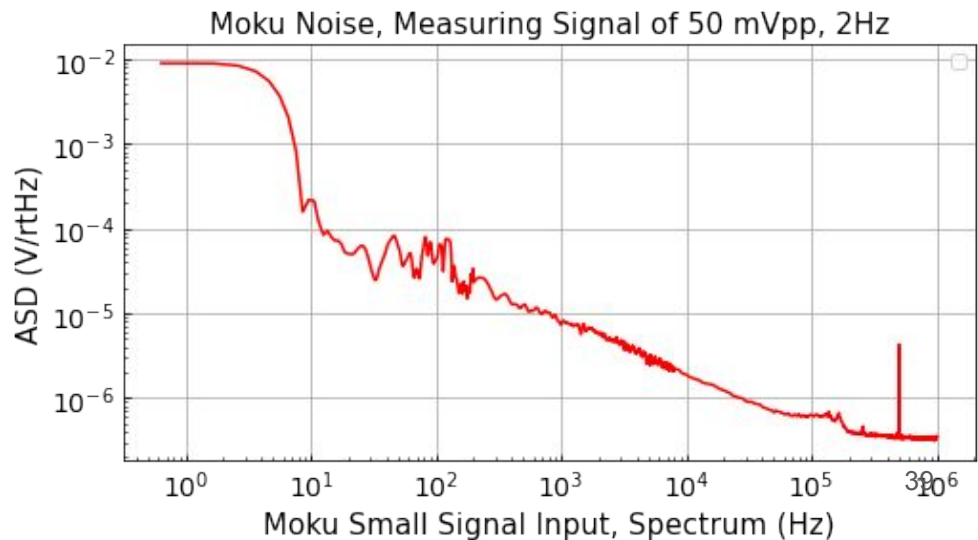
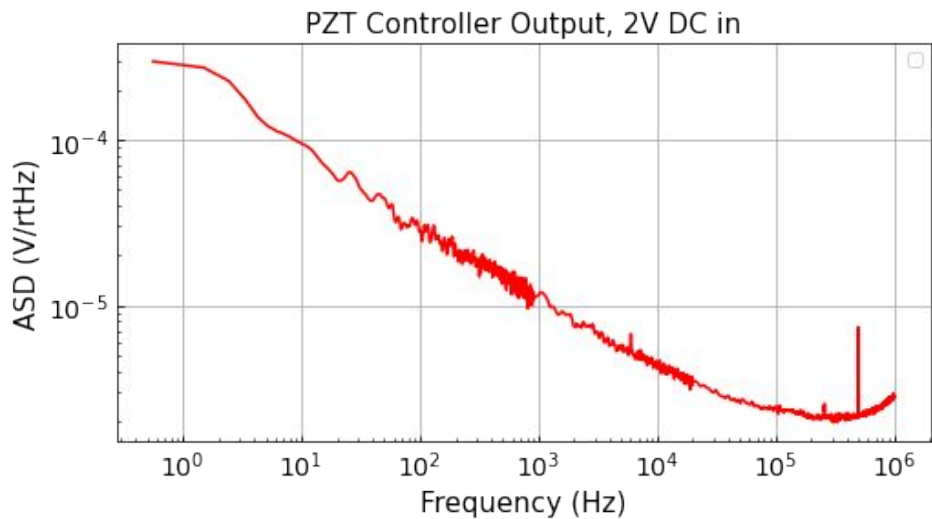
Frequency Noise

- Measured spectrum while laser was locked



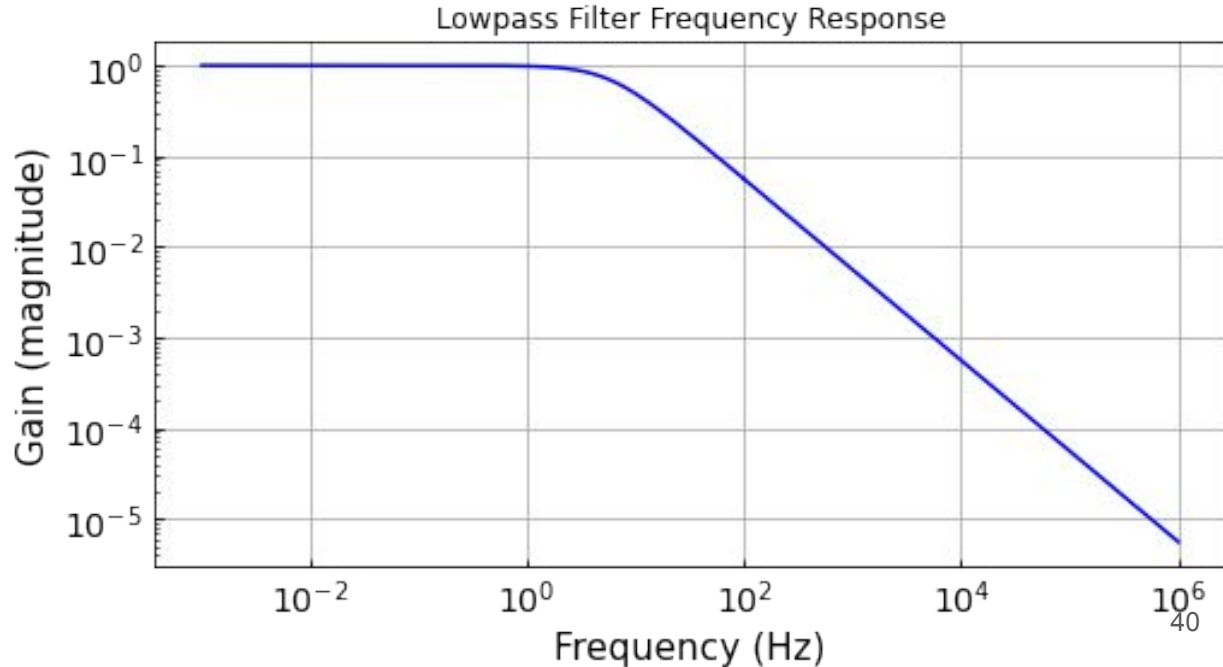
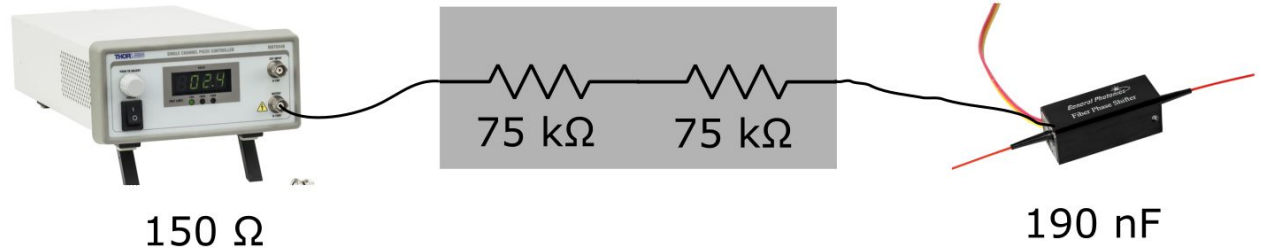
Loop-Locking Noise

- There is noise associated with outputting a signal on the Moku and from using a piezo controller to amplify our signal
- Measured piezo controller output spectrum with a DC voltage input
- Set Moku to output a sine wave with a small amplitude and measured spectrum of the output



Low-pass Filter

- Suppress noise from fiber stretcher controls at high frequencies
- Use capacitance of fiber stretcher as our capacitor



Lowpass Filtering

